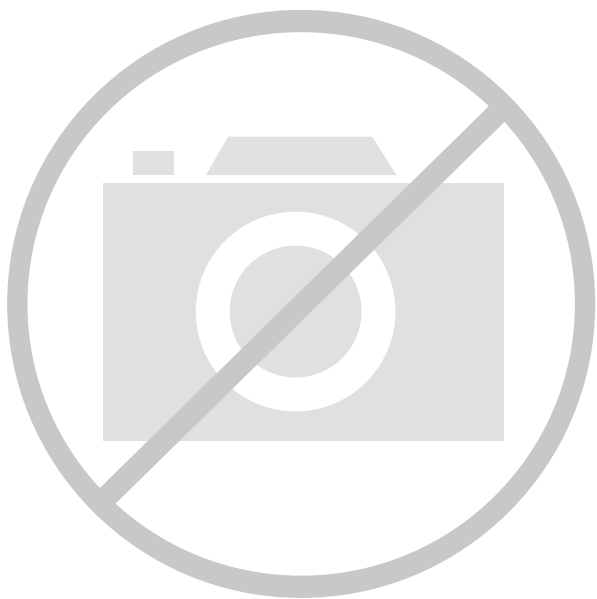




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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	684
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	72
Number of Gates	4000
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	84-LCC (J-Lead)
Supplier Device Package	84-PLCC (29.31x29.31)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a1240a-1plg84i

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Table 2-3 • Electrical Specifications

Symbol	Parameter	Commercial		Industrial		Military		Units
		Min.	Max.	Min.	Max.	Min.	Max.	
VOH ¹	(IOH = –10 mA) ²	2.4	–	–	–	–	–	V
	(IOH = –6 mA)	3.84	–	–	–	–	–	V
	(IOH = –4 mA)	–	–	3.7	–	3.7	–	V
VOL ¹	(IOL = 10 mA) ²	–	0.5	–	–	–	–	V
	(IOL = 6 mA)	–	0.33	–	0.40	–	0.40	V
VIL		–0.3	0.8	–0.3	0.8	–0.3	0.8	V
VIH		2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	V
Input Transition Time t _R , t _F ²		–	500	–	500	–	500	ns
C _{IO} I/O capacitance ^{2,3}		–	10	–	10	–	10	pF
Standby Current, ICC ⁴ (typical = 1 mA)		–	2	–	10	–	20	mA
Leakage Current ⁵		–10	+10	–10	+10	–10	+10	μA
ICC(D)	Dynamic VCC supply current. See the Power Dissipation section.							

Notes:

1. Only one output tested at a time. VCC = minimum.
2. Not tested, for information only.
3. Includes worst-case PG176 package capacitance. VOUT = 0 V, f = 1 MHz
4. All outputs unloaded. All inputs = VCC or GND, typical ICC = 1 mA. ICC limit includes IPP and ISV during normal operations.
5. VOUT, VIN = VCC or GND.

Package Thermal Characteristics

The device junction to case thermal characteristic is θ_{jc} , and the junction to ambient air characteristic is θ_{ja} . The thermal characteristics for θ_{ja} are shown with two different air flow rates.

Maximum junction temperature is 150°C.

A sample calculation of the absolute maximum power dissipation allowed for a PQ160 package at commercial temperature and still air is as follows:

$$\frac{\text{Max. junction temp. (°C)} - \text{Max. ambient temp. (°C)}}{\theta_{ja} \text{ °C/W}} = \frac{150^{\circ}\text{C} - 70^{\circ}\text{C}}{33^{\circ}\text{C/W}} = 2.4 \text{ W}$$

EQ 1

Table 2-4 • Package Thermal Characteristics

Package Type*	Pin Count	θ_{jc}	θ_{ja} Still Air	θ_{ja} 300 ft./min.	Units
Ceramic Pin Grid Array	100	5	35	17	°C/W
	132	5	30	15	°C/W
	176	8	23	12	°C/W
Ceramic Quad Flatpack	172	8	25	15	°C/W
Plastic Quad Flatpack ¹	100	13	48	40	°C/W
	144	15	40	32	°C/W
	160	15	38	30	°C/W
Plastic Leaded Chip Carrier	84	12	37	28	°C/W
Very Thin Quad Flatpack	100	12	43	35	°C/W
Thin Quad Flatpack	176	15	32	25	°C/W

Notes: (Maximum Power in Still Air)

1. Maximum power dissipation values for PQFP packages are 1.9 W (PQ100), 2.3 W (PQ144), and 2.4 W (PQ160).
2. Maximum power dissipation for PLCC packages is 2.7 W.
3. Maximum power dissipation for VQFP packages is 2.3 W.
4. Maximum power dissipation for TQFP packages is 3.1 W.

Power Dissipation

$$P = [\text{ICC standby} + \text{ICC active}] * V_{CC} + \text{IOL} * \text{VOL} * N + \text{IOH} * (V_{CC} - \text{VOH}) * M$$

EQ 2

where:

ICC standby is the current flowing when no inputs or outputs are changing

ICC active is the current flowing due to CMOS switching.

IOL and IOH are TTL sink/source currents.

VOL and VOH are TTL level output voltages.

N is the number of outputs driving TTL loads to VOL.

M is the number of outputs driving TTL loads to VOH.

An accurate determination of N and M is problematical because their values depend on the family type, design details, and on the system I/O. The power can be divided into two components: static and active.

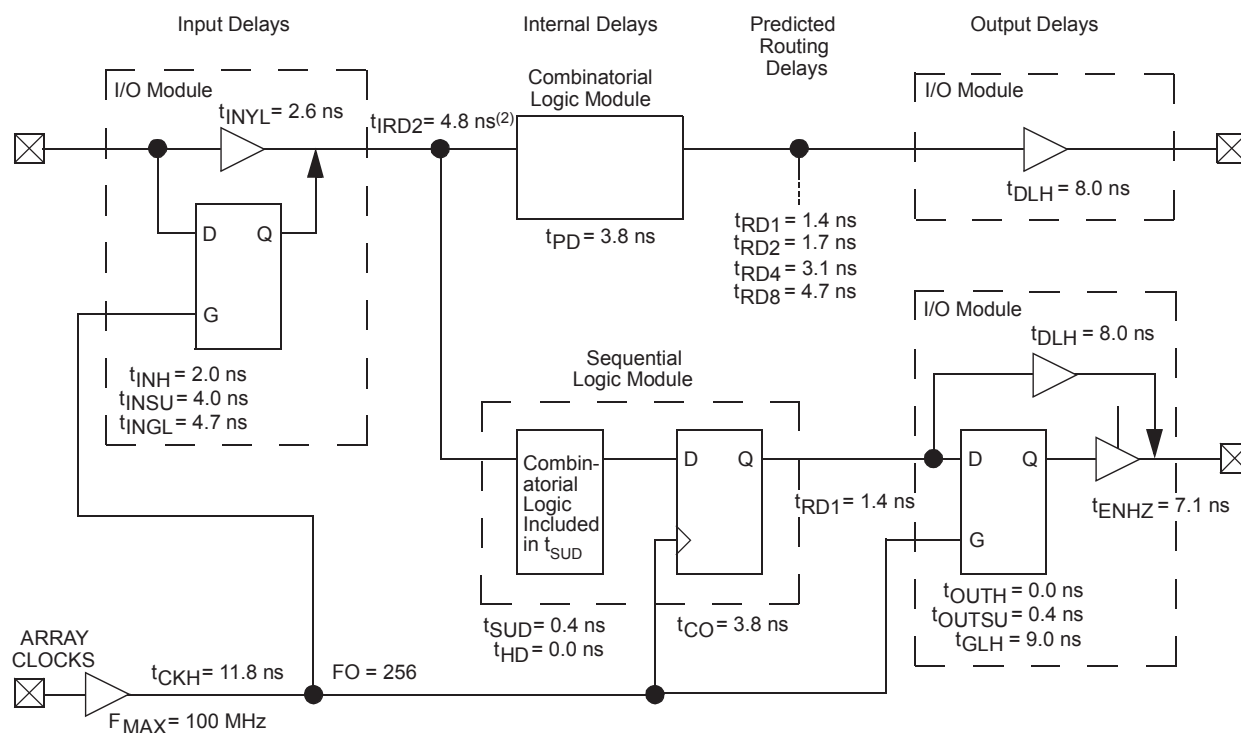
Determining Average Switching Frequency

To determine the switching frequency for a design, you must have a detailed understanding of the data input values to the circuit. The following guidelines are meant to represent worst-case scenarios so that they can be generally used to predict the upper limits of power dissipation. These guidelines are given in [Table 2-8](#).

Table 2-8 • Guidelines for Predicting Power Dissipation

Data	Value
Logic Modules (m)	80% of modules
Inputs switching (n)	# inputs/4
Outputs switching (p)	# output/4
First routed array clock loads (q1)	40% of sequential modules
Second routed array clock loads (q2)	40% of sequential modules
Load capacitance (C_L)	35 pF
Average logic module switching rate (f_m)	F/10
Average input switching rate (f_n)	F/5
Average output switching rate (f_p)	F/10
Average first routed array clock rate (f_{q1})	F
Average second routed array clock rate (f_{q2})	F/2

ACT 2 Timing Model¹



Notes:

1. Values shown for A1240A-2 at worst-case commercial conditions.
2. Input module predicted routing delay

Figure 2-1 • Timing Model

Timing Derating Factor (Temperature and Voltage)

Table 2-9 • Timing Derating Factor (Temperature and Voltage)

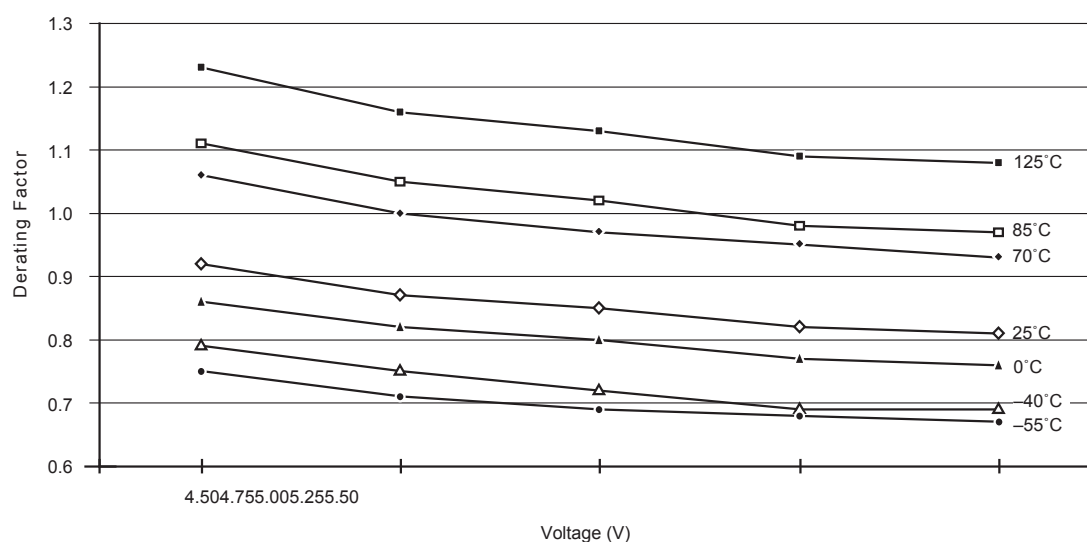
(Commercial Minimum/Maximum Specification) x	Industrial		Military	
	Min.	Max.	Min.	Max.
	0.69	1.11	0.67	1.23

Table 2-10 • Timing Derating Factor for Designs at Typical Temperature ($T_J = 25^\circ\text{C}$) and Voltage (5.0 V)

(Commercial Maximum Specification) x	0.85
--------------------------------------	------

Table 2-11 • Temperature and Voltage Derating Factors (normalized to Worst-Case Commercial, $T_J = 4.75\text{ V}$, 70°C)

	-55	-40	0	25	70	85	125
4.50	0.75	0.79	0.86	0.92	1.06	1.11	1.23
4.75	0.71	0.75	0.82	0.87	1.00	1.05	1.13
5.00	0.69	0.72	0.80	0.85	0.97	1.02	1.13
5.25	0.68	0.69	0.77	0.82	0.95	0.98	1.09
5.50	0.67	0.69	0.76	0.81	0.93	0.97	1.08



Note: This derating factor applies to all routing and propagation delays.

Figure 2-9 • Junction Temperature and Voltage Derating Curves (normalized to Worst-Case Commercial, $T_J = 4.75\text{ V}$, 70°C)

A1225A Timing Characteristics

Table 2-12 • A1225A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

Logic Module Propagation Delays ¹		–2 Speed ³		–1 Speed		Std. Speed		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	
t _{PD1}	Single Module		3.8		4.3		5.0	ns
t _{CO}	Sequential Clock to Q		3.8		4.3		5.0	ns
t _{GO}	Latch G to Q		3.8		4.3		5.0	ns
t _{RS}	Flip-Flop (Latch) Reset to Q		3.8		4.3		5.0	ns
Predicted Routing Delays²								
t _{RD1}	FO = 1 Routing Delay		1.1		1.2		1.4	ns
t _{RD2}	FO = 2 Routing Delay		1.7		1.9		2.2	ns
t _{RD3}	FO = 3 Routing Delay		2.3		2.6		3.0	ns
t _{RD4}	FO = 4 Routing Delay		2.8		3.1		3.7	ns
t _{RD8}	FO = 8 Routing Delay		4.4		4.9		5.8	ns
Sequential Timing Characteristics^{3,4}								
t _{SUD}	Flip-Flop (Latch) Data Input Setup	0.4		0.4		0.5		ns
t _{HD}	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		ns
t _{SUENA}	Flip-Flop (Latch) Enable Setup	0.8		0.9		1.0		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	4.5		5.0		6.0		ns
t _{WASYN}	Flip-Flop (Latch) Clock Asynchronous Pulse Width	4.5		5.0		6.0		ns
t _A	Flip-Flop Clock Input Period	9.4		11.0		13.0		ns
t _{INH}	Input Buffer Latch Hold	0.0		0.0		0.0		ns
t _{INSU}	Input Buffer Latch Setup	0.4		0.4		0.5		ns
t _{OUTH}	Output Buffer Latch Hold	0.0		0.0		0.0		ns
t _{OUTSU}	Output Buffer Latch Setup	0.4		0.4		0.5		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency		105.0		90.0		75.0	MHz

Notes:

- For dual-module macros, use t_{PD1} + t_{RD1} + t_{PDn}, t_{CO} + t_{RD1} + t_{PDn}, or t_{PD1} + t_{RD1} + t_{SUD}—whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
- Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the DirectTime Analyzer utility.
- Setup and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.

A1240A Timing Characteristics (continued)

Table 2-16 • A1240A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Module Input Propagation Delays			–2 Speed		–1 Speed		Std. Speed		Units
Parameter/Description			Min.	Max.	Min.	Max.	Min.	Max.	
t _{INYH}	Pad to Y High			2.9		3.3		3.8	ns
t _{INYL}	Pad to Y Low			2.6		3.0		3.5	ns
t _{INGH}	G to Y High			5.0		5.7		6.6	ns
t _{INGL}	G to Y Low			4.7		5.4		6.3	ns
Input Module Predicted Input Routing Delays*									
t _{IRD1}	FO = 1 Routing Delay			4.2		4.8		5.6	ns
t _{IRD2}	FO = 2 Routing Delay			4.8		5.4		6.4	ns
t _{IRD3}	FO = 3 Routing Delay			5.4		6.1		7.2	ns
t _{IRD4}	FO = 4 Routing Delay			5.9		6.7		7.9	ns
t _{IRD8}	FO = 8 Routing Delay			7.9		8.9		10.5	ns
Global Clock Network									
t _{CKH}	Input Low to High	FO = 32		10.2		11.0		12.8	ns
		FO = 256		11.8		13.0		15.7	
t _{CKL}	Input High to Low	FO = 32		10.2		11.0		12.8	ns
		FO = 256		12.0		13.2		15.9	
t _{PWH}	Minimum Pulse Width High	FO = 32	3.8		4.5		5.5		ns
		FO = 256	4.1		5.0		5.8		
t _{PWL}	Minimum Pulse Width Low	FO = 32	3.8		4.5		5.5		ns
		FO = 256	4.1		5.0		5.8		
t _{CKSW}	Maximum Skew	FO = 32		0.5		0.5		0.5	ns
		FO = 256		2.5		2.5		2.5	
t _{SUEXT}	Input Latch External Setup	FO = 32	0.0		0.0		0.0		ns
		FO = 256	0.0		0.0		0.0		
t _{HEXT}	Input Latch External Hold	FO = 32	7.0		7.0		7.0		ns
		FO = 256	11.2		11.2		11.2		
t _P	Minimum Period	FO = 32	8.1		9.1		11.1		ns
		FO = 256	8.8		10.0		11.7		
f _{MAX}	Maximum Frequency	FO = 32		125.0		110.0		90.0	ns
		FO = 256		115.0		100.0		85.0	

Note: *These parameters should be used for estimating device performance. Optimization techniques may further reduce delays by 0 to 4 ns. Routing delays are for typical designs across worst-case operating conditions. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

A1240A Timing Characteristics (continued)

Table 2-17 • A1240A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

TTL Output Module Timing ¹		-2 Speed		-1 Speed		Std. Speed		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	
t _{DLH}	Data to Pad High		8.0		9.0		10.6	ns
t _{DHL}	Data to Pad Low		10.1		11.4		13.4	ns
t _{ENZH}	Enable Pad Z to High		8.9		10.0		11.8	ns
t _{ENZL}	Enable Pad Z to Low		11.7		13.2		15.5	ns
t _{ENHZ}	Enable Pad High to Z		7.1		8.0		9.4	ns
t _{ENLZ}	Enable Pad Low to Z		8.4		9.5		11.1	ns
t _{GLH}	G to Pad High		9.0		10.2		11.9	ns
t _{GHL}	G to Pad Low		11.2		12.7		14.9	ns
d _{TLH}	Delta Low to High		0.07		0.08		0.09	ns/pF
d _{THL}	Delta High to Low		0.12		0.13		0.16	ns/pF
CMOS Output Module Timing ¹								
t _{DLH}	Data to Pad High		10.2		11.5		13.5	ns
t _{DHL}	Data to Pad Low		8.4		9.6		11.2	ns
t _{ENZH}	Enable Pad Z to High		8.9		10.0		11.8	ns
t _{ENZL}	Enable Pad Z to Low		11.7		13.2		15.5	ns
t _{ENHZ}	Enable Pad High to Z		7.1		8.0		9.4	ns
t _{ENLZ}	Enable Pad Low to Z		8.4		9.5		11.1	ns
t _{GLH}	G to Pad High		9.0		10.2		11.9	ns
t _{GHL}	G to Pad Low		11.2		12.7		14.9	ns
d _{TLH}	Delta Low to High		0.12		0.13		0.16	ns/pF
d _{THL}	Delta High to Low		0.09		0.10		0.12	ns/pF

Notes:

1. Delays based on 50 pF loading.
2. SSO information can be found at www.microsemi.com/soc/techdocs/appnotes/board_consideration.aspx.

Table 2-20 • A1280A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

TTL Output Module Timing ¹		–2 Speed		–1 Speed		Std. Speed		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	
t _{DLH}	Data to Pad High		8.1		9.0		10.6	ns
t _{DHL}	Data to Pad Low		10.2		11.4		13.4	ns
t _{ENZH}	Enable Pad Z to High		9.0		10.0		11.8	ns
t _{ENZL}	Enable Pad Z to Low		11.8		13.2		15.5	ns
t _{ENHZ}	Enable Pad High to Z		7.1		8.0		9.4	ns
t _{ENLZ}	Enable Pad Low to Z		8.4		9.5		11.1	ns
t _{GLH}	G to Pad High		9.0		10.2		11.9	ns
t _{GHL}	G to Pad Low		11.3		12.7		14.9	ns
d _{TLH}	Delta Low to High		0.07		0.08		0.09	ns/pF
d _{THL}	Delta High to Low		0.12		0.13		0.16	ns/pF
CMOS Output Module Timing ¹								
t _{DLH}	Data to Pad High		10.3		11.5		13.5	ns
t _{DHL}	Data to Pad Low		8.5		9.6		11.2	ns
t _{ENZH}	Enable Pad Z to High		9.0		10.0		11.8	ns
t _{ENZL}	Enable Pad Z to Low		11.8		13.2		15.5	ns
t _{ENHZ}	Enable Pad High to Z		7.1		8.0		9.4	ns
t _{ENLZ}	Enable Pad Low to Z		8.4		9.5		11.1	ns
t _{GLH}	G to Pad High		9.0		10.2		11.9	ns
t _{GHL}	G to Pad Low		11.3		12.7		14.9	ns
d _{TLH}	Delta Low to High		0.12		0.13		0.16	ns/pF
d _{THL}	Delta High to Low		0.09		0.10		0.12	ns/pF

Notes:

1. Delays based on 50 pF loading.
2. SSO information can be found at www.microsemi.com/soc/techdocs/appnotes/board_consideration.aspx.

Pin Descriptions

CLKA Clock A (Input)

TTL Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

CLKB Clock B (Input)

TTL Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

DCLK Diagnostic Clock (Input)

TTL Clock input for diagnostic probe and device programming. DCLK is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

GND Ground

Low supply voltage.

I/O Input/Output (Input, Output)

The I/O pin functions as an input, output, three-state, or bidirectional buffer. Input and output levels are compatible with standard TTL and CMOS specifications. Unused I/O pins are automatically driven Low by the ALS software.

MODE Mode (Input)

The MODE pin controls the use of multifunction pins (DCLK, PRA, PRB, SDI). When the MODE pin is High, the special functions are active. When the MODE pin is Low, the pins function as I/Os. To provide Actionprobe capability, the MODE pin should be terminated to GND through a 10K resistor so that the MODE pin can be pulled High when required.

NC No Connection

This pin is not connected to circuitry within the device.

PRA Probe A (Output)

The Probe A pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe B pin to allow real-time diagnostic output of any signal path within the device. The Probe A pin can be used as a user-defined I/O when debugging has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. PRA is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

PRB Probe B (Output)

The Probe B pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe A pin to allow real-time diagnostic output of any signal path within the device. The Probe B pin can be used as a user-defined I/O when debugging has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. PRB is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

SDI Serial Data Input (Input)

Serial data input for diagnostic probe and device programming. SDI is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

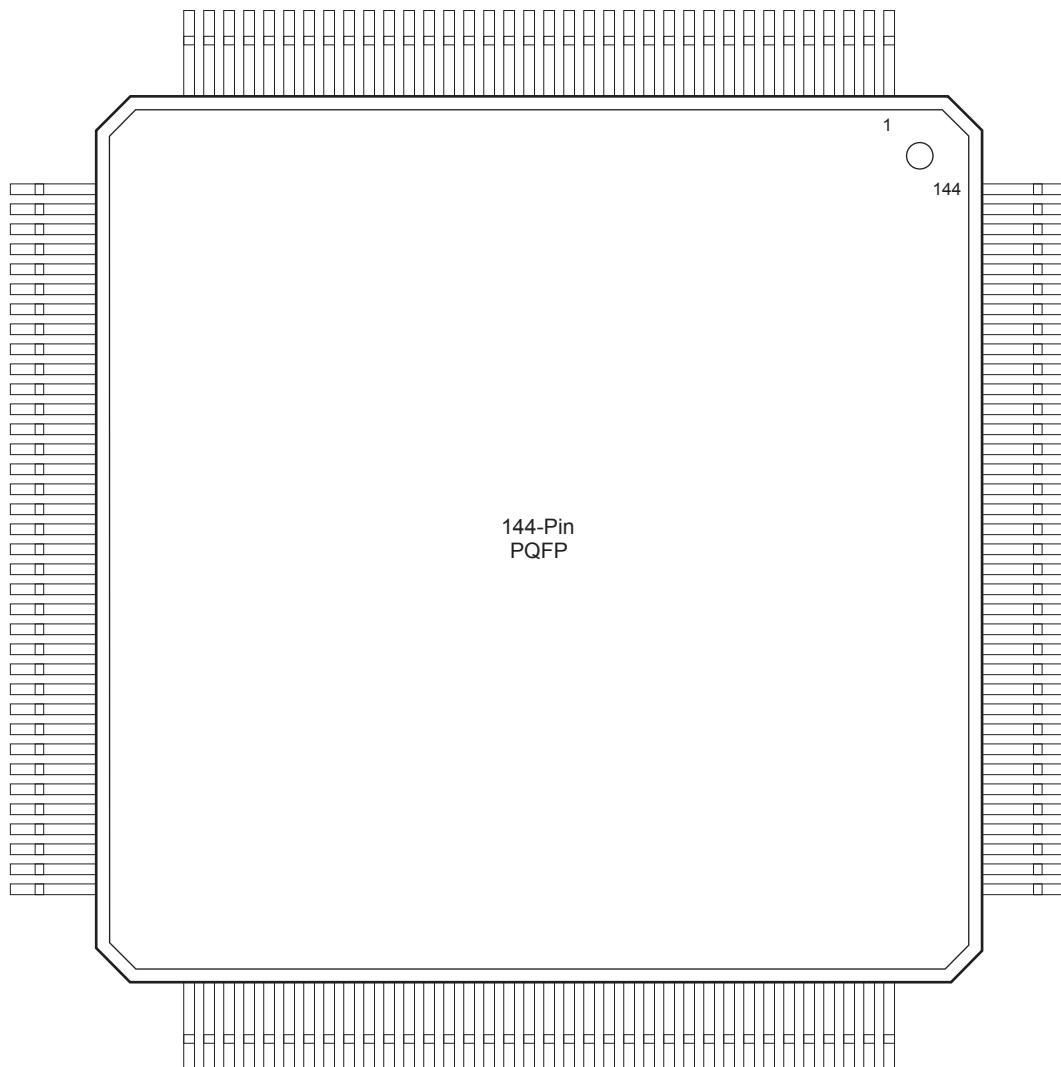
SDO Serial Data Output (Output)

Serial data output for diagnostic probe. SDO is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

VCC 5.0 V Supply Voltage

High supply voltage.

PQ144



Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

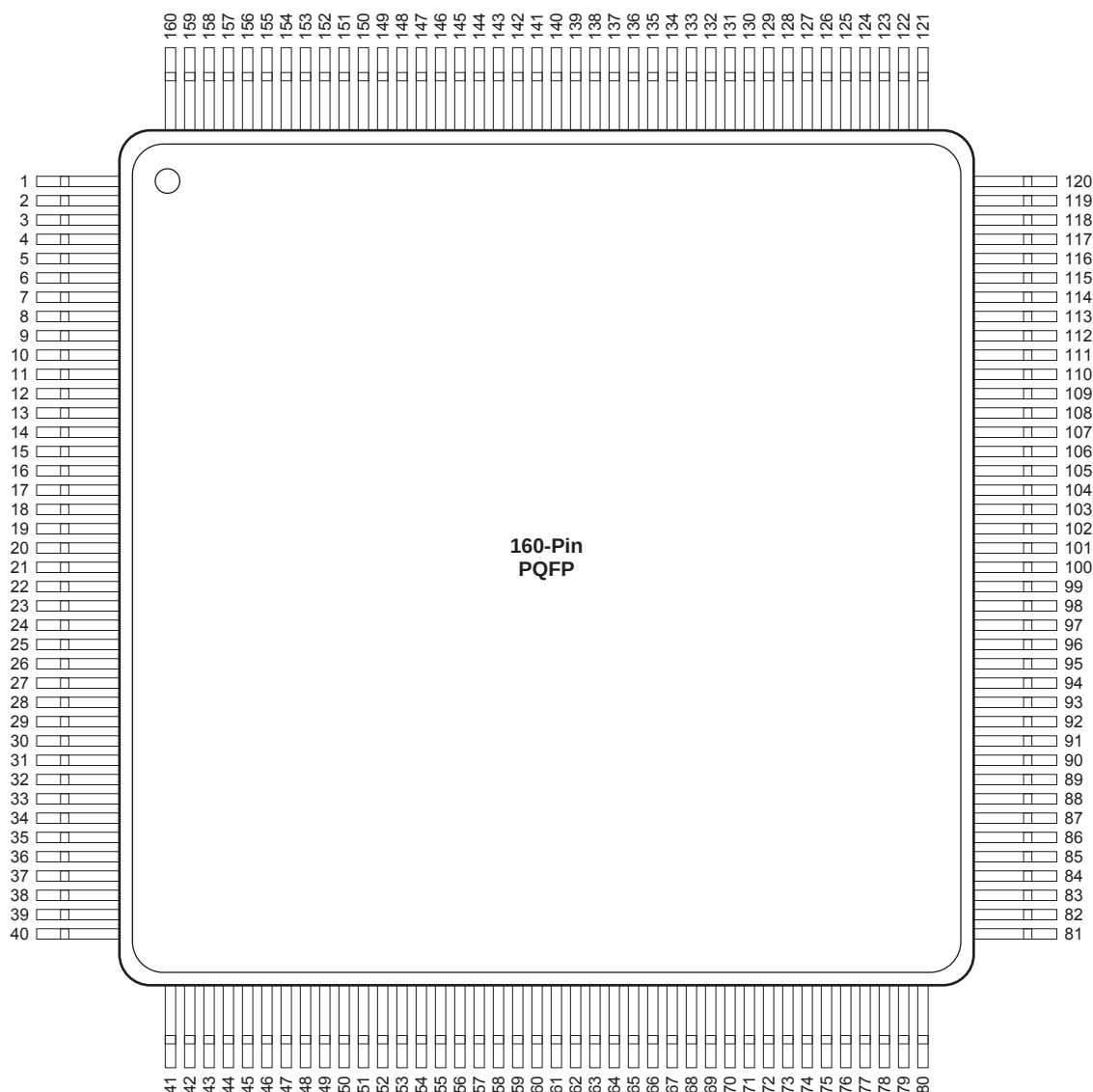
PQ144	
Pin Number	A1240A Function
2	MODE
9	GND
10	GND
11	GND
18	VCC
19	VCC
20	VCC
21	VCC
28	GND
29	GND
30	GND
44	GND
45	GND
46	GND
54	VCC
55	VCC
56	VCC
64	GND
65	GND
71	SDO
79	GND
80	GND
81	GND
88	GND

PQ144	
Pin Number	A1240A Function
89	VCC
90	VCC
91	VCC
92	VCC
93	VCC
100	GND
101	GND
102	GND
110	SDI, I/O
116	GND
117	GND
118	GND
123	PRA, I/O
125	CLKA, I/O
126	VCC
127	VCC
128	VCC
130	CLKB, I/O
132	PRB, I/O
136	GND
137	GND
138	GND
144	DCLK, I/O

Notes:

1. All unlisted pin numbers are user I/Os.
2. MODE pin should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

PQ160



Note: This is the top view of the package

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

VQ100	
Pin Number	A1225A Function
2	MODE
7	GND
14	VCC
15	VCC
20	GND
32	GND
38	VCC
44	GND
50	SDO
55	GND
62	GND
63	VCC

VQ100	
Pin Number	A1225A Function
64	VCC
65	VCC
70	GND
77	SDI, I/O
82	GND
85	PRA, I/O
87	CLKA, I/O
88	VCC
90	CLKB, I/O
92	PRB, I/O
94	GND
100	DCLK, I/O

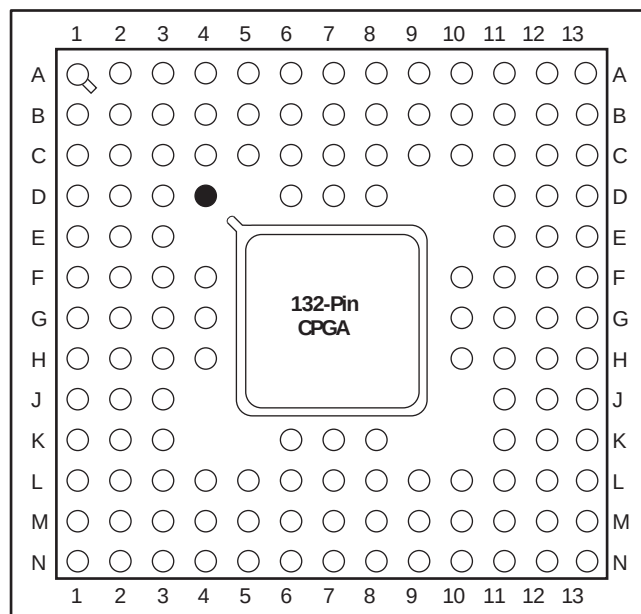
Notes:

1. All unlisted pin numbers are user I/Os.
2. MODE pin should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

TQ176		
Pin Number	A1240A Function	A1280A Function
1	GND	GND
2	MODE	MODE
8	NC	NC
10	NC	I/O
11	NC	I/O
13	NC	VCC
18	GND	GND
19	NC	I/O
20	NC	I/O
22	NC	I/O
23	GND	GND
24	NC	VCC
25	VCC	VCC
26	NC	I/O
27	NC	I/O
28	VCC	VCC
29	NC	I/O
33	NC	NC
37	NC	I/O
38	NC	NC
45	GND	GND
52	NC	VCC
54	NC	I/O
55	NC	I/O
57	NC	NC
61	NC	I/O
64	NC	I/O
66	NC	I/O
67	GND	GND
68	VCC	VCC
74	NC	I/O
77	NC	NC
78	NC	I/O
80	NC	I/O

TQ176		
Pin Number	A1240A Function	A1280A Function
82	NC	VCC
86	NC	I/O
87	SDO	SDO
89	GND	GND
96	NC	I/O
97	NC	I/O
101	NC	NC
103	NC	I/O
106	GND	GND
107	NC	I/O
108	NC	I/O
109	GND	GND
110	VCC	VCC
111	GND	GND
112	VCC	VCC
113	VCC	VCC
114	NC	I/O
115	NC	I/O
116	NC	VCC
121	NC	NC
124	NC	I/O
125	NC	I/O
126	NC	NC
133	GND	GND
135	SDI, I/O	SDI, I/O
136	NC	I/O
140	NC	VCC
143	NC	I/O
144	NC	I/O
145	NC	NC
147	NC	I/O
151	NC	I/O
152	PRA, I/O	PRA, I/O
154	CLKA, I/O	CLKA, I/O

PG132



● Orientation Pin

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

PG132	
Pin Number	A1240A Function
A1	MODE
B5	GND
B6	CLKB, I/O
B7	CLKA, I/O
B8	PRA, I/O
B9	GND
B12	SDI, I/O
C3	DCLK, I/O
C5	GND
C6	PRB, I/O
C7	VCC
C9	GND
D7	VCC
E3	GND
E11	GND
E12	GND
F4	GND
G2	VCC

PG132	
Pin Number	A1240A Function
G3	VCC
G4	VCC
G10	VCC
G11	VCC
G12	VCC
G13	VCC
H13	GND
J2	GND
J3	GND
J11	GND
K7	VCC
K12	GND
L5	GND
L7	VCC
L9	GND
M9	GND
N12	SDO

Notes:

1. All unlisted pin numbers are user I/Os.
2. MODE pin should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

